WHAT IS CLAIMED IS:

1. A socket guider for testing of electronic parts, the socket guider comprising:

a pair of guider bodies provided to support both ends of an electronic part to be inserted into an elongated test slit into which a contact terminal-side portion of the electronic part is inserted; and

a pair of elastic supporters replaceably coupled to the guider bodies, respectively, and configured to maintain a posture of the electronic part by elastically supporting both ends of the electronic part while the contact terminal-side portion is inserted into the test slit or in a state in which the contact terminal-side portion has been inserted into the test slit;

wherein the pair of guider bodies are disposed on both sides of the test slit, respectively, in a direction in which the test slit is elongated; and

wherein the pair of elastic supports are allocated to the pair of guider bodies, respectively, and are detachably installed in the guider bodies, respectively,

wherein:

a guide groove is elongated in each of the guider bodies in a direction, in which the electronic part is moved, in order to guide the electronic part through movement in a process in which the electronic part is inserted into the test slit, and a coupling depression is formed at one point of the guide groove;

each of the elastic supports is a ball plunger provided in a structure in which the ball plunger is inserted into the coupling depressing; and

a ball of the ball plunger presses the electronic part while being elastically supported by a spring.